APT19F100J

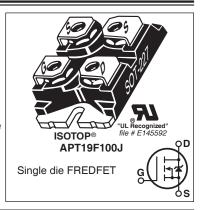




1000V, 19A, 0.46 Ω Max, $t_{rr} \leq$ 270ns

N-Channel FREDFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent niose immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- ZVS phase shifted and other full full bridge
- · Half bridge
- PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I _D	Continuous Drain Current @ T _C = 25°C	19	
	Continuous Drain Current @ T _C = 100°C	12	А
I _{DM}	Pulsed Drain Current ^①	120	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy®	1875	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	16	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			460	W	
$R_{ hetaJC}$	Junction to Case Thermal Resistance			0.27 °C/W		
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15		C/VV	
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
V _{Isolation}	RMS Voltage (50-60hHz Sinusoidal Wavefomr Ffrom Terminals to Mounting Base for 1 Min.)	2500			V	
W _T	Package Weight		1.03		OZ	
			29.2		g	
Torque	Terminals and Mounting Screws.			10	in·lbf	
				1.1 ^{WW}	w.NataSl	

050-8080 Peet 40.5008

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250\mu A$	1000			V
$\Delta V_{BR(DSS)}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, $I_D = 250\mu A$		1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	V _{GS} = 10V, I _D = 16A		0.39	0.46	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	\/ -\/ -2.5m/	3	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}, I_D = 2.5 \text{mA}$		-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 1000V$ $T_{J} = 25^{\circ}C$			250	
DSS		$V_{GS} = 0V$ $T_J = 125^{\circ}C$			1000	μA
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V			±100	nA

Dynamic Characteristics

T₁ = 25°C unless otherwise specified

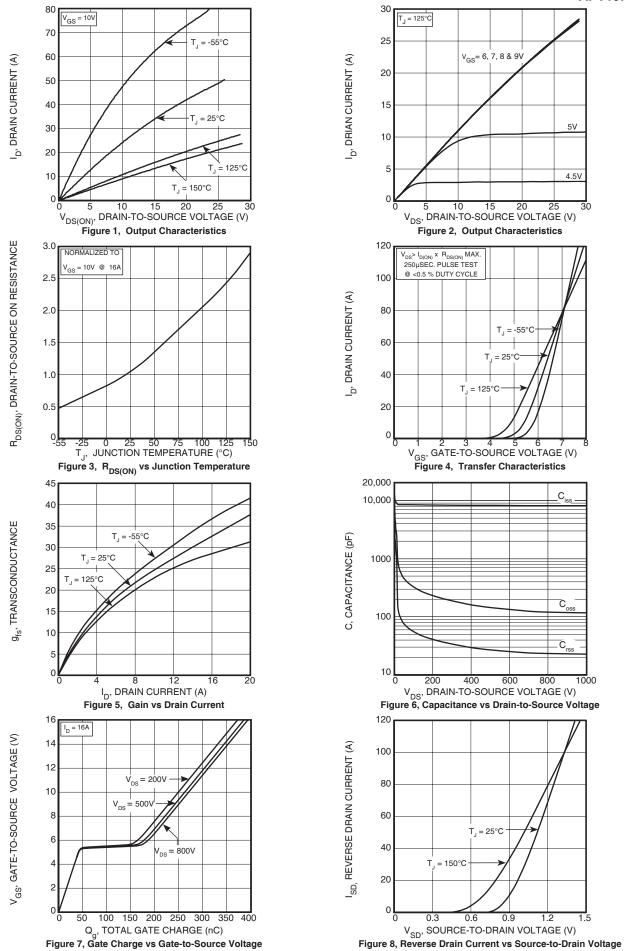
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
g _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 16A		34		S
C _{iss}	Input Capacitance	V 0V V 05V		8500		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		115		
C _{oss}	Output Capacitance	1 - 111112		715		
$C_{o(cr)} \textcircled{4}$	Effective Output Capacitance, Charge Related	V 0V V 0V to 007V		290		pF
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 667V$		150		
Q _g	Total Gate Charge	V 0 1 10V 1 10A		260		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 16A,$ $V_{DS} = 500V$		46		nC
Q _{gd}	Gate-Drain Charge	v _{DS} = 500V		125		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		39		
t _r	Current Rise Time	V _{DD} = 667V, I _D = 16A		35		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 2.2\Omega^{\textcircled{6}}, V_{GG} = 15V$		130		1 115
t _f	Current Fall Time	1		33		1

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Is	Continuous Source Current (Body Diode)	MOSFET symbol showing the			100	A
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)	os S		120	^
V _{SD}	Diode Forward Voltage	$I_{SD} = 16A, T_{J} = 25^{\circ}C, V_{GS} = 0V$	'		1.1	V
t _{rr}	Reverse Recovery Time	T _J = 25°C		230	270	no
rr		T _J = 125°C		500	640	ns
Q _{rr}	Reverse Recovery Charge	$I_{SD} = 16A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$		13		μC
rr		$di_{SD}/dt = 100A/\mu s$ $T_J = 125^{\circ}C$		35		μC
1	Reverse Recovery Current	T _J = 25°C		11		Α
'rrm		T _J = 125°C		15		^
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 16A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 6$ $T_{J} = 125^{\circ}C$	67V,		25	V/ns

- 1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25$ °C, L = 14.65mH, $R_G = 2.2\Omega$, $I_{AS} = 16$ A.
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- Q C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
 C C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(cr)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -2.47E-7/V_{DS}^2 + 4.36E-8/V_{DS} + 8.44E-11.
- (6) R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



0.14

0.12

0.10

0.08

0.06

0.04

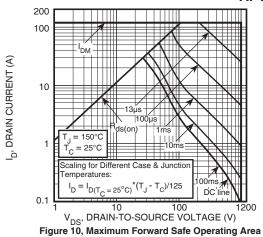
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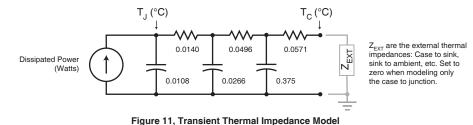
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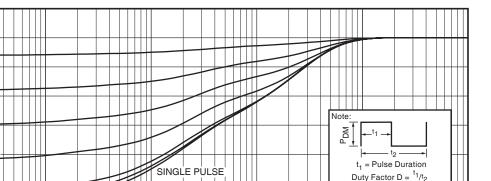
0.05

 $Z_{\theta JC}$, THERMAL IMPEDANCE (°C/W)



Peak $T_J = P_{DM} \times Z_{\theta JC} + T_C$





 $\frac{10^{\text{-}4}}{\text{RECTANGULAR PULSE DURATION (seconds)}} \frac{10^{\text{-}2}}{\text{RECTANGULAR PULSE DURATION (seconds)}}$ Figure 12. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

SOT-227 (ISOTOP®) Package Outline

